extract a contour line shape feature of the suspicious region and compare the contour line shape feature with a pre-created standard template to obtain a comparison result; and

determine that the suspicious region contains a high atomic number matter based on the classification result and the comparison result.

9. The system of claim 8, wherein a contour line of the suspicious region is derived using an edge extraction algorithm and a (θ, ρ) feature curve of the contour line is derived.

10. An apparatus for inspecting goods comprising:

means for processing a transmission image of inspected goods to obtain a suspicious region;

means for extracting local texture features of the suspicious region and classifying the local texture features of the suspicious region based on a pre-created model to obtain a classification result;

means for extracting a contour line shape feature of the suspicious region and comparing the contour line shape feature with a pre-created standard template to obtain a comparison result; and

means for determining that the suspicious region contains a high atomic number matter based on the classification result and the comparison result.

11. A non-transitory computer-readable medium comprising computer-executable instructions for causing one or more processors and/or memory to perform a method comprising the steps of:

obtaining a transmission image of inspected goods;

processing the transmission image to obtain a suspicious region;

extracting local texture features of the suspicious region and classifying the local texture features of the suspicious region based on a pre-created model to obtain a classification result;

extracting a contour line shape feature of the suspicious region and comparing the contour line shape feature with a pre-created standard template to obtain a comparison result; and

determining that the suspicious region contains a high atomic number matter based on the classification result and the comparison result.